

Formal Analysis of Fault Injection Effects on RISC-V Microarchitecture Models

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APPROACH

MOTIVATION

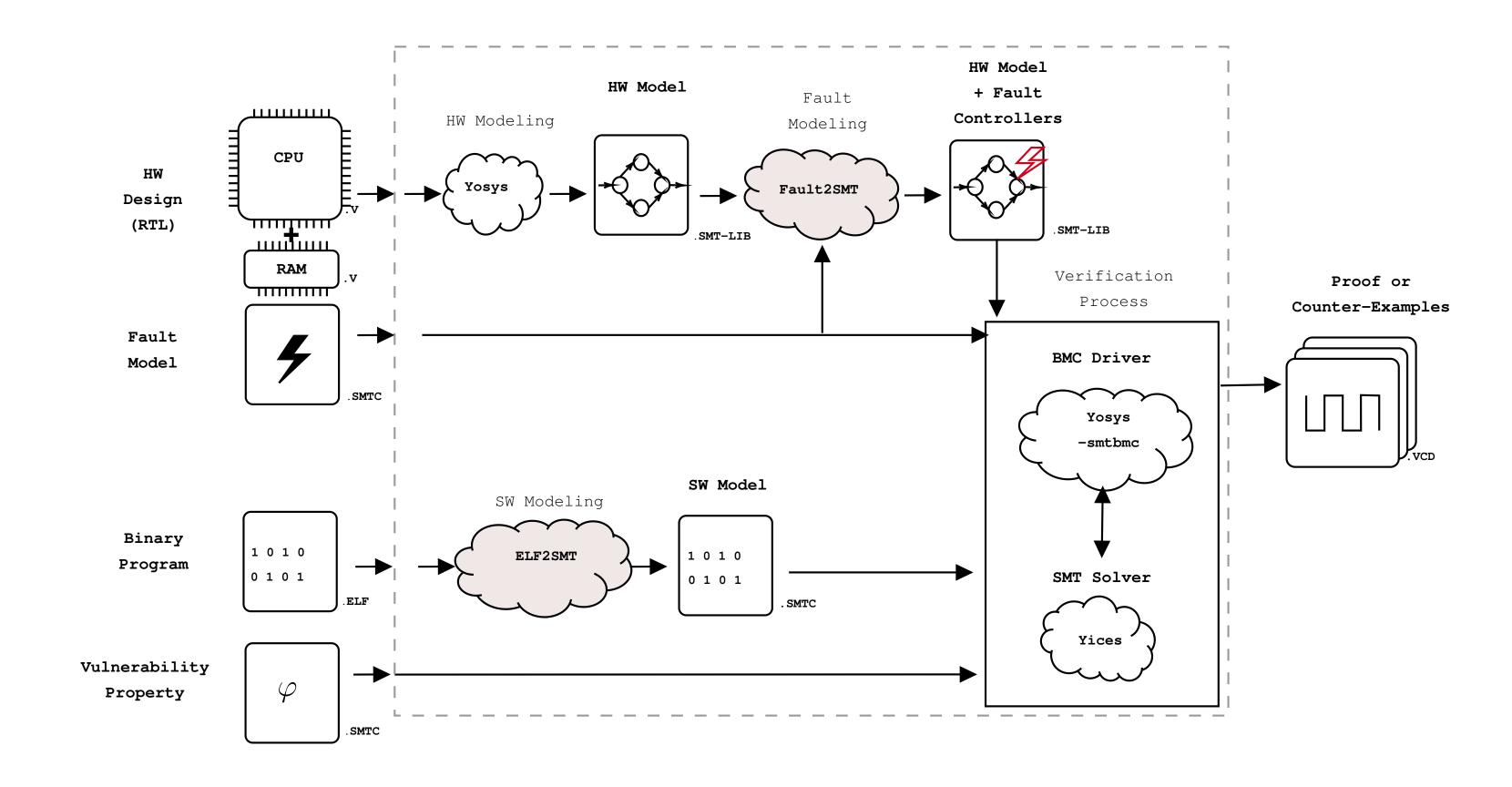
- Fault injection (FI) [1] is a threat to embedded systems
- Security analysis under FI attacks is performed either using:
 - Tests on real platforms [2,3]
 - Simulation [4,5]
 - Formal methods [6]
- Common fault models considered at the ISA level:
 - Instruction replacement
- Register corruption
- Many fault effects depend on the hardware implementation and are not directly addressable at the ISA level [7], e.g.,
 - Pipeline
 - Speculative execution
- A precise knowledge of the microarchitecture is essential for:
 - A better understanding of the effect of faults
 - A better security evaluation

Contributions

- Develop a workflow that encompasses the SH/HW to identify harmful faults
- Illustrate the approach on a use case
- Exhibit new fault effects that are difficult to model at the ISA level

Workflow

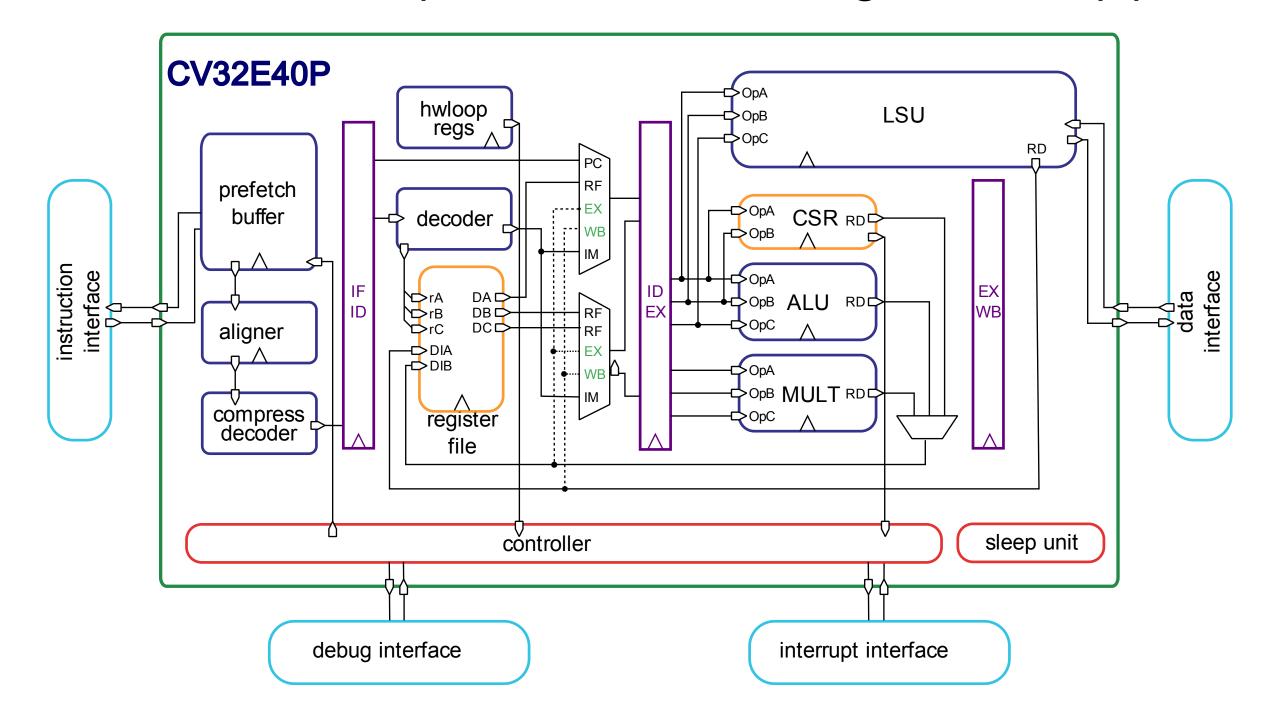
- Yosys produces a formal model (SMT-Lib)
- Software program, FI effects and FI timings are modeled by SMT constraints
- Security properties are expressed with SMT assertions
- Yices SMT Solver uses bounded model checking to find vulnerabilities
- Yosys generates counter-examples (VCD) highlighting fault propagation in the design



USE CASE

ARCHITECTURE: CV32E40P

A 32-bit RISC-V processor with a 4-stage, in-order pipeline



SOFTWARE: VERIFYPIN

- VerifyPin program [8] compares two 4-digit codes stored in memory
- Embedded countermeasures against FI:
 - Hardened booleans
 - Loop count verification
 - Inline call
- Attacker's goal: bypassing the authentication mechanism
- Security property: an incorrect password cannot allow authentication

FAULT VULNERABILITY RESULTS

- Investigate single-FI attacks on the logic gates and wires of the design during the VerifyPin execution
- About 6 CPU hours of calculation on an 80-core cluster were needed
- 50 faults injections were identified (2 of them are detailed below on the left)

Module	Wire	Timing	Effect
id_controller	operand_a_fw_mux_sel_o	@57	bit-flip
prefetch_buffer	status_cnt_n	@21-26	bit-set

- We identify vulnerabilities already known in the literature [7], e.g., faulting the forwarding mechanism by targeting the operand_a_fw_mux_sel_o signal
- We highlight that a fault injection on the prefetch buffer (PFB) (i.e., status_cnt_n) leads to effects that are difficult to model at the ISA level:
 - 1. The fault can force the execution of instructions speculatively fetched in the PFB,
 - 2. Next instructions are potentially pushed in the pipeline in an incorrect order,
 - 3. The program jumps to an incorrect address at the next branch instruction.

Module	Wires	Cycle	
		-Og flag	-Os flag
aligner	instr_valid_o	18	
	branch_i	47	
	update_state	47	
controller	deassert_we_o	19	65
	halt_id_o	19	65
	is_decoding_o	19	65
	jump_in_dec	57	68
	operand_a_fw_mux_sel_o	57	65
	pc_set_o		66
decoder	alu_en		65
	alu_op_a_mux_sel_o	57	65
	alu_op_b_mux_sel_o	57	65
	ctrl_transfer_insn	57	65, 68
	ctrl_transfer_insn_in_id_o		65
	regfile_alu_waddr_sel_o	19	
	regfile_alu_we_o	19	
	alu_cmp_result	58	66
ex_stage	mult_multicycle_o	19	65
	regfile_alu_we_fw_o	20	
	empty_o		64
fifo	status_cnt_n	21 - 26	63
	alu_op_a_mux_sel	57	65
	alu_op_b_mux_sel	57	65
	alu_vec_mode	57	65
	alu_vec_mode_ex_o	58	66
id_stage		20	00
	apu_en_ex_o bmask b mux	46	61
	branch_in_ex_o	40	66
	branch taken ex	58	66
	halt_id	19	65
	_	19	65
	id_valid_o	57	65
	operand_a_fw_mux_sel	57	
	pc_set_o	 	66
	reg_d_alu_is_reg_a_id	57	65
	regfile_alu_waddr_mux_sel	19	
	regfile_alu_we_ex_o	20	
	regfile_alu_we_id	19	
if_stage	branch_req	10	66
	instr_valid	18	64
	instr_valid_id_o	19	65
	is_fetch_failed_o	19	65
_	mulh_CS		28, 64
mult	mulh_NS		27, 63
	multicycle_o	19	65
prefetch_ctrl	flush_cnt_q		26, 28-29, 39-4
			50-51, 61-64
	next_flush_cnt		25, 27-28, 38-3
			49-50, 60-63

PERSPECTIVES

- Classify fault injection effects: visible/non-visible at the ISA level
- Improve the scalability of the approach

- Study more complex processors, e.g., CVA6
- Determine the minimal design to model new fault effects at the ISA level

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